



## 65536-BIT(8192-WORD BY 8-BIT)MASK-PROGRAMMABLE ROM

## ABSOLUTE MAXIMUM RATINGS (Note 1)

Temperature under bias	-10°C ~ +80°C
Storage temperature	-65°C ~ +150°C
All input or output voltage (Note 2)	-0.3V ~ +7V

Note 1 Stresses above those listed may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods affects device reliability.

2 With respect to Ground

## RECOMMENDED OPERATING CONDITIONS (Ta=0~70°C)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V <sub>CC</sub>	Supply voltage (Note 1)	4.5	5	5.5	V
GND	Supply voltage		0		V
V <sub>IH</sub>	High level input voltage	2.4		V <sub>CC</sub> +0.1	V
V <sub>IL</sub>	Low level input voltage	-0.1		0.45	V

Note 1 Need 1μF ceramic capacitor between V<sub>CC</sub> and GND.

D.C. CHARACTERISTICS (Ta=0~70°C, V<sub>CC</sub>=5V±10%, unless otherwise noted)

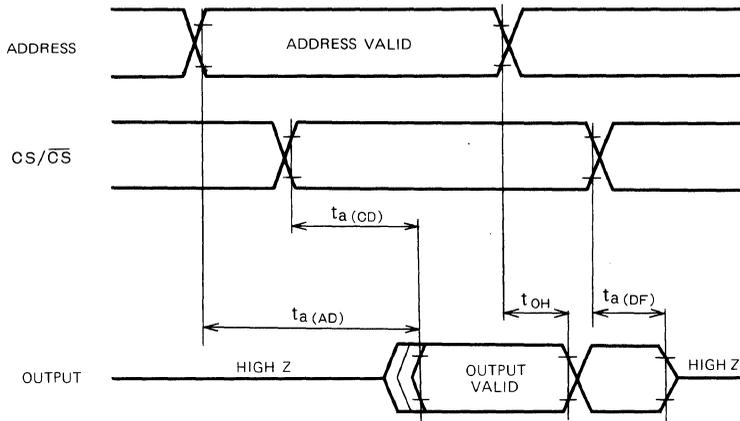
Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
I <sub>LI</sub>	Input load current		-10		10	μA
I <sub>LO</sub>	Output leakage current		-10		10	μA
I <sub>CC1</sub>	V <sub>CC</sub> current standby	CS/ $\overline{CS}$ = V <sub>IL</sub> /V <sub>IH</sub>			10	mA
		CS/ $\overline{CS}$ = 0.2V/V <sub>CC</sub> -0.2V			50	μA
I <sub>CC2</sub>	V <sub>CC</sub> current active	CS/ $\overline{CS}$ = V <sub>IH</sub> /V <sub>IL</sub> , Output open			40	mA
V <sub>IL</sub>	Input low voltage		-0.1		0.6	V
V <sub>IH</sub>	Input high voltage		2.2		V <sub>CC</sub> +0.1	V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> =2.1 mA			0.45	V
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> =-400 μA	2.4			V

A.C. CHARACTERISTICS (Ta=0~70°C, V<sub>CC</sub>=5V±10%, V<sub>IH</sub>=2.4V, V<sub>IL</sub>=0.45V, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
t <sub>a</sub> (AD)	Address to output delay	CS/ $\overline{CS}$ = V <sub>IH</sub> /V <sub>IL</sub>			350	ns
t <sub>a</sub> (CD)	Chip select to output delay				350	ns
t <sub>a</sub> (DF)	Chip select to output float				200	ns
t <sub>OH</sub>	Output hold from address	CS/ $\overline{CS}$ = V <sub>IH</sub> /V <sub>IL</sub>	0			ns

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**A.C. WAVEFORMS**



Test Conditions for A.C. Characteristics  
 Input voltage:  $V_{IL}=0.45V$ ,  $V_{IH}=2.4V$   
 Input rise and fall times:  $\leq 20ns$   
 Reference voltage at timing measurement: Inputs 0.8V and 2V  
 Output load: 1 TTL gate,  $C_L=100pF$       Outputs 0.8V and 2V

**CAPACITANCE** ( $T_a=25^\circ C$ ,  $f=1MHz$ )

Symbol	Parameter	Text conditions	Limits			Unit
			Min	Typ	Max	
$C_{IN}$	Input Capacitance	$V_{IN}=0V$			10	pF
$C_{OUT}$	Output Capacitance	$V_{OUT}=0V$			15	pF